Product data sheet

# A5G23H110N Airfast RF Power GaN Amplifier Rev. 2 — 18 October 2023



## **1** General description

This 13.8 W asymmetrical Doherty RF power GaN amplifier is designed for cellular base station applications requiring very wide instantaneous bandwidth capability covering the frequency range of 2300 to 2400 MHz.

This part is characterized and performance is guaranteed for applications operating in the 2300 to 2400 MHz band. There is no guarantee of performance when this part is used in applications designed outside of these frequencies.

# 2 Features and benefits

- · High terminal impedances for optimal broadband performance
- · Improved linearized error vector magnitude with next generation signal
- Able to withstand extremely high output VSWR and broadband operating conditions
- · Designed for low complexity linearization systems
- · Optimized for massive MIMO active antenna systems for 5G base stations

# 3 Typical performance

Table 1. 2300 MHz — Typical Doherty single-carrier W-CDMA reference circuit performance $V_{DD}$  = 48 Vdc,  $I_{DQA}$  = 50 mA,  $V_{GSB}$  = -4.7 Vdc,  $P_{out}$  = 13.8 W Avg., Input Signal PAR = 9.9 dB @ 0.01% Probability onCCDF.<sup>[1]</sup>

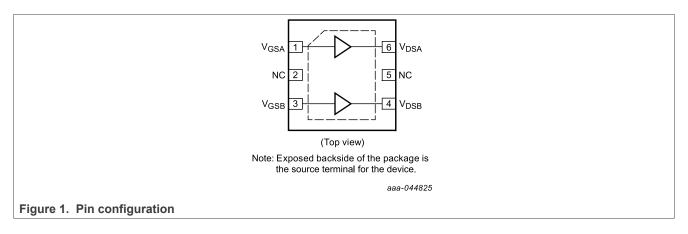
| Frequency | G <sub>ps</sub><br>(dB) | η <sub>D</sub><br>(%) | Output PAR<br>(dB) | ACPR<br>(dBc) |
|-----------|-------------------------|-----------------------|--------------------|---------------|
| 2300 MHz  | 16.3                    | 56.6                  | 8.5                | -29.1         |
| 2350 MHz  | 16.1                    | 56.5                  | 8.6                | -30.8         |
| 2400 MHz  | 16.2                    | 56.3                  | 8.8                | -32.4         |

[1] All data measured with device soldered to NXP reference circuit.



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## 4 Pinning information

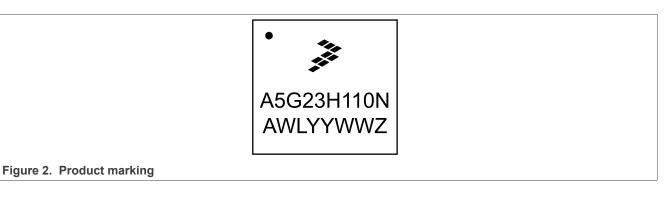


# 5 Ordering information

### Table 2. Ordering information

| Device       | Tape and Reel Information                               | Package     |
|--------------|---|-------------|
| A5G23H110NT4 | T4 Suffix = 2,500 Units, 16 mm Tape Width, 13-inch Reel | DFN 7 × 6.5 |

# 6 Product marking



#### Table 3. Product marking trace code

| Identifier | Description         |
|------------|---------------------|
| A          | Assembly location   |
| WL         | Wafer lot indicator |
| YYWW       | Date code           |
| Z          | Assembly lot        |

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## 7 Limiting values

#### Table 4. Limiting values

| Rating  | Symbol            | Value       | Unit |
|---|-------------------|-------------|------|
| Drain-Source Voltage  | V <sub>DSS</sub>  | 125         | Vdc  |
| Gate-Source Voltage   | V <sub>GS</sub>   | -16, 0      | Vdc  |
| Operating Voltage   | V <sub>DD</sub>   | 55          | Vdc  |
| Maximum Forward Gate Current, $I_{G (A+B)}$ , @ $T_{C} = 25^{\circ}C$ | I <sub>GMAX</sub> | 13.3        | mA   |
| Storage Temperature Range   | T <sub>stg</sub>  | -65 to +150 | °C   |
| Case Operating Temperature Range                                      | T <sub>C</sub>    | -55 to +150 | °C   |
| Maximum Channel Temperature   | T <sub>CH</sub>   | 225         | °C   |

## 8 Recommended operating conditions

#### Table 5. Recommended operating conditions

| Characteristic    | Symbol          | Value | Unit |
|-------------------|-----------------|-------|------|
| Operating Voltage | V <sub>DD</sub> | 48    | Vdc  |

## **9** Thermal characteristics

#### Table 6. Thermal characteristics

| Characteristic  | Symbol                     | Value              | Unit |
|---|----------------------------|--------------------|------|
| Thermal Resistance by Infrared Measurement, Active Die Surface-to-Case Case Temperature 117°C, $P_D$ = 15.1 W     | R <sub>θJC</sub> (IR)      | 2.7 <sup>[1]</sup> | °C/W |
| Thermal Resistance by Finite Element Analysis, Channel-to-Case<br>Case Temperature 117°C, P <sub>D</sub> = 15.1 W | R <sub>θCHC</sub><br>(FEA) | 5.9 <sup>[2]</sup> | °C/W |

[1] Refer to AN1955, Thermal Measurement Methodology of RF Power Amplifiers. Go to http://www.nxp.com/RF and search for AN1955.

 $[P] R_{\theta CHC} (FEA) must be used for purposes related to reliability and limitations on maximum channel temperature. MTTF may be estimated by the expression MTTF (hours) = 10^{[A + B/(T + 273)]}, where T is the channel temperature in degrees Celsius, <math>A = -11.6$  and B = 9129.

# **10 ESD protection characteristics**

#### Table 7. ESD protection characteristics

| Test Methodology                      | Class |
|---------------------------------------|-------|
| Human Body Model (per JS-001-2017)    | 1A    |
| Charge Device Model (per JS-002-2014) | C3    |

## **11 Moisture sensitivity level**

#### Table 8. Moisture sensitivity level

| Test Methodology                     | Rating | Package Peak Temperature | Unit |
|--------------------------------------|--------|--------------------------|------|
| Per JESD22-A113, IPC/JEDEC J-STD-020 | 3      | 260                      | °C   |

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# **12** Electrical characteristics

## **12.1 DC characteristics**

### 12.1.1 DC characteristics — off characteristics

#### Table 9. DC characteristics — off characteristics

#### $(T_A = 25^{\circ}C \text{ unless otherwise noted})$

| Characteristic  | Symbol             | Min  | Тур | Max | Unit |
|---|--------------------|------|-----|-----|------|
| Off characteristics <sup>[1]</sup>                            |                    |      |     | 1   |      |
| Off-State Drain Leakage                                       | I <sub>D(BR)</sub> |      |     |     | mAdc |
| (V <sub>DS</sub> = 150 Vdc, V <sub>GS</sub> = –8 Vdc) Carrier |                    | _    | _   | 2.1 |      |
| (V <sub>DS</sub> = 150 Vdc, V <sub>GS</sub> = –8 Vdc) Peaking |                    | _    |     | 3.9 |      |
| Off-State Gate Leakage  | I <sub>GLK</sub>   |      |     |     | mAdc |
| (V <sub>DS</sub> = 48 Vdc, V <sub>GS</sub> = –8 Vdc) Carrier  |                    | -1.0 | _   | _   |      |
| (V <sub>DS</sub> = 48 Vdc, V <sub>GS</sub> = –8 Vdc) Peaking  |                    | -1.0 | _   | —   |      |

[1] Each side of device measured separately.

#### **12.1.2 DC characteristics — on characteristics**

#### Table 10. DC characteristics — on characteristics

 $(T_A = 25^{\circ}C \text{ unless otherwise noted})$ 

| Characteristic   | Symbol              | Min  | Тур  | Мах  | Unit |
|--|---------------------|------|------|------|------|
| On characteristics — Side A, carrier   |                     |      |      | -    |      |
| Gate Threshold Voltage<br>(V <sub>DS</sub> = 10 Vdc, I <sub>D</sub> = 4.6 mAdc)                              | V <sub>GS(th)</sub> | -4.6 | -3.0 | -1.9 | Vdc  |
| Gate Quiescent Voltage<br>(V <sub>DD</sub> = 48 Vdc, I <sub>DA</sub> = 60 mAdc, Measured in Functional Test) | V <sub>GSA(Q)</sub> | -3.0 | -2.4 | -2.0 | Vdc  |
| Gate-Source Leakage Current<br>(V <sub>DS</sub> = 150 Vdc, V <sub>GS</sub> = –8 Vdc)                         | I <sub>GSS</sub>    | -2.1 | —    | —    | mAdc |
| On characteristics — Side B, peaking   |                     |      |      |      |      |
| Gate Threshold Voltage<br>(V <sub>DS</sub> = 10 Vdc, I <sub>D</sub> = 8.7 mAdc)                              | V <sub>GS(th)</sub> | -4.6 | -3.0 | -1.9 | Vdc  |
| Gate-Source Leakage Current<br>(V <sub>DS</sub> = 150 Vdc, V <sub>GS</sub> = –8 Vdc)                         | I <sub>GSS</sub>    | -3.9 |      | _    | mAdc |

## 12.2 Functional tests

#### Table 11. Functional tests

(In NXP Doherty Production  $ATE^{[1]}$  Test Fixture,  $T_A = 25^{\circ}$ C unless otherwise noted, 50 ohm system)<sup>[2]</sup>  $V_{DD} = 48$  Vdc,  $I_{DQA} = 60$  mA,  $V_{GSB} = (V_t - 1.25)$  Vdc,  $P_{out} = 14$  W Avg., f = 2400 MHz, 1-tone CW.

| Characteristic                                | Symbol           | Min  | Тур  | Max  | Unit |
|---|------------------|------|------|------|------|
| Power Gain                                    | G <sub>ps</sub>  | 15.5 | 17.9 | 20.5 | dB   |
| Drain Efficiency                              | η <sub>D</sub>   | 47.0 | 57.0 | _    | %    |
| Saturated Power<br>(Pulsed CW, 5% Duty Cycle) | P <sub>sat</sub> | 46.8 | 48.7 | _    | dBm  |

[1] ATE is a socketed test environment.

[2] Internally matched part.

## 12.3 Wideband ruggedness

### Table 12. Wideband ruggedness

(In NXP Doherty Reference Circuit,  $T_A = 25^{\circ}$ C unless otherwise noted, 50 ohm system)<sup>[1]</sup>  $I_{DQA} = 50 \text{ mA}$ ,  $V_{GSB} = -4.7 \text{ Vdc}$ , f = 2350 MHz, Additive White Gaussian Noise (AWGN) with 10 dB PAR.

| Characteristic   | Symbol                | Min | Тур | Мах | Unit |
|--|-----------------------|-----|-----|-----|------|
| ISBW of 400 MHz at 55 Vdc, 27.5 W Avg. Modulated Output Power  | No Device Degradation |     |     |     |      |
| (3 dB Input Overdrive from 13.8 W Avg. Modulated Output Power) |                       |     |     |     |      |

[1] All data measured with device soldered to NXP reference circuit.

## 12.4 Typical performance

#### Table 13. Typical performance

(In NXP Doherty Reference Circuit,  $T_A = 25^{\circ}$ C unless otherwise noted, 50 ohm system)<sup>[1]</sup>  $V_{DD} = 48$  Vdc,  $I_{DQA} = 50$  mA,  $V_{GSB} = -4.7$  Vdc, 2300–2400 MHz Bandwidth.

| Characteristic   | Symbol             | Min | Тур   | Мах | Unit  |
|--|--------------------|-----|-------|-----|-------|
| Fast CW, 27 ms sweep   |                    |     |       |     |       |
| Saturated Power  | P <sub>sat</sub>   |     | 92    | —   | W     |
| AM/PM<br>(Maximum value measured at saturated power across the<br>2300–2400 MHz bandwidth) | Φ                  |     | -10   | _   | o     |
| Gain Variation @ Avg. Power over Temperature<br>(–40°C to +85°C)                           | ΔG                 | —   | 0.028 | _   | dB/°C |
| Output Power Variation @ Saturated Power over Temperature (-40°C to +85°C)                 | ΔP <sub>sat</sub>  | —   | 0.002 | _   | dB/°C |
| Single-carrier W-CDMA, unclipped   |                    |     |       |     |       |
| Gain Flatness in 100 MHz Bandwidth @ P <sub>out</sub> = 13.8 W Avg.                        | G <sub>F</sub>     |     | 0.2   | —   | dB    |
| 2-tone CW  |                    |     |       |     |       |
| VBW Resonance Point<br>(IMD Third Order Intermodulation Inflection Point)                  | VBW <sub>res</sub> | —   | 180   | —   | MHz   |

[1] All data measured with device soldered to NXP reference circuit.

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#### Correct biasing sequence for GaN depletion mode amplifiers in a Doherty configuration

#### Bias ON the device

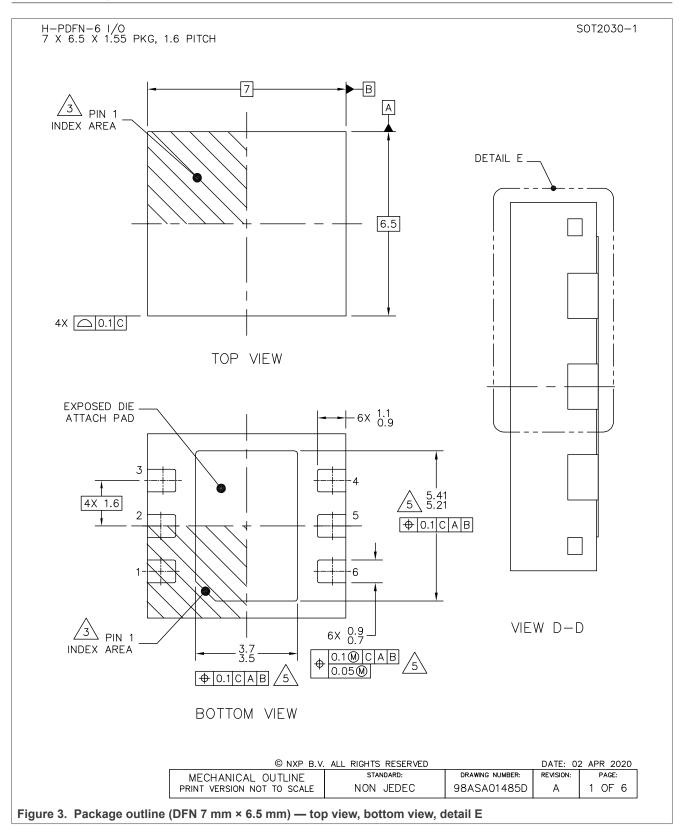
- 1. Set gate voltage  $V_{GSA}$  and  $V_{GSB}$  to –5 V.
- 2. Set drain voltage  $V_{DSA}$  and  $V_{DSB}$  to nominal supply voltage (+48 V).
- 3. Increase V<sub>GSA</sub> (carrier side) until I<sub>DQA</sub> current is attained.
- 4. Increase  $V_{GSB}$  (peaking side) to target bias voltage.
- 5. Apply RF input power to desired level.

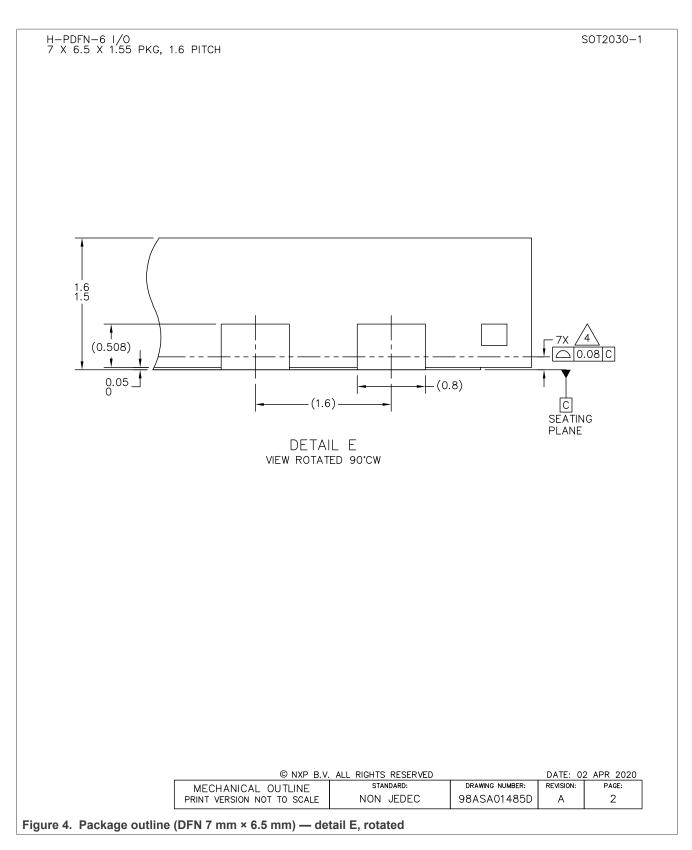
#### Bias OFF the device

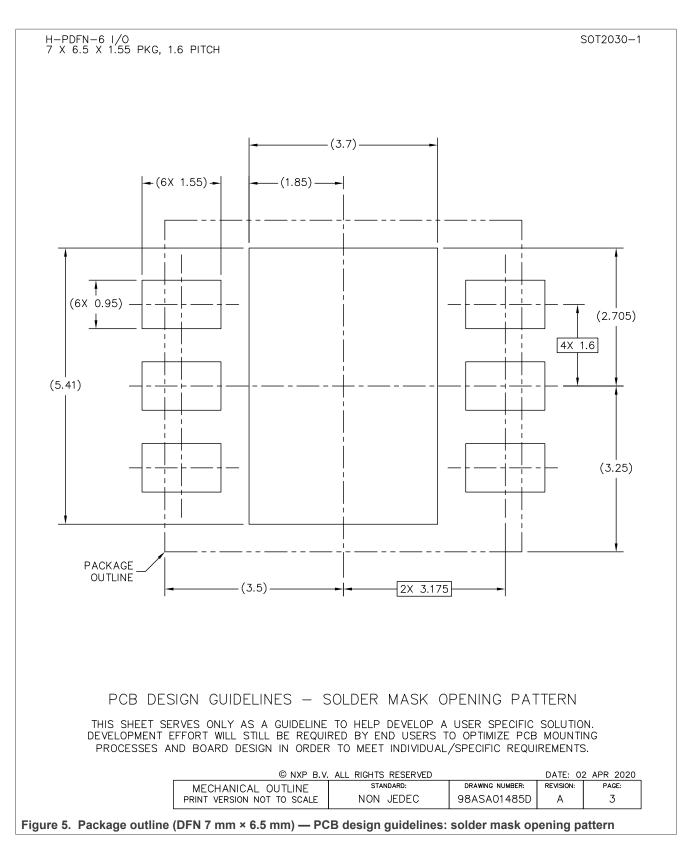
- 1. Disable RF input power.
- 2. Adjust gate voltage  $V_{GSA}$  and  $V_{GSB}$  to –5 V.
- 3. Adjust drain voltage  $V_{DSA}$  and  $V_{DSB}$  to 0 V. Allow adequate time for drain voltage to reduce to 0 V from external drain capacitors.
- 4. Disable  $V_{GSA}$  and  $V_{GSB}$ .

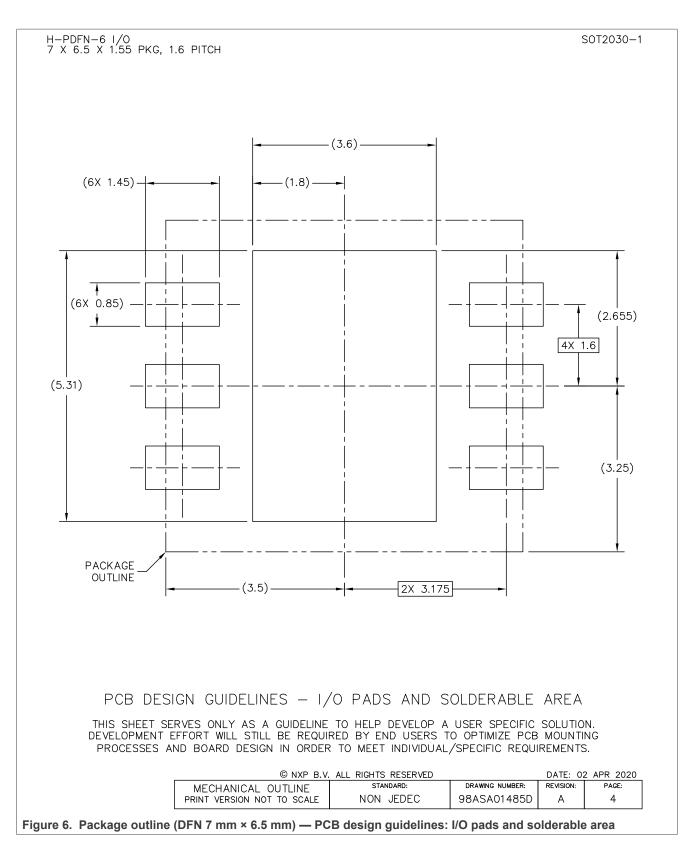
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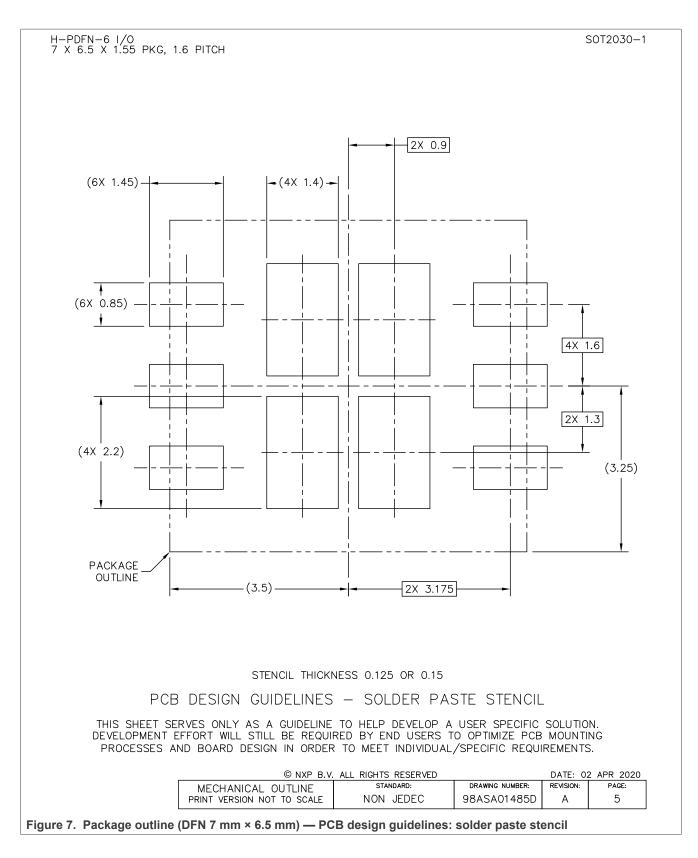
# 13 Package information











### **NXP Semiconductors**

# A5G23H110N

SOT2030-1

### Airfast RF Power GaN Amplifier

#### H-PDFN-6 I/O 7 X 6.5 X 1.55 PKG, 1.6 PITCH

NOTES:

1. ALL DIMENSIONS ARE IN MILLIMETERS.

2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

3. PIN 1 FEATURE SHAPE, SIZE AND LOCATION MAY VARY.

4, coplanarity applies to leads and die attach flag.

5. RADIUS ON LEAD AND DIE ATTACH FLAG IS OPTIONAL.

| MECHANICAL OUTLINE         | STANDARD: | DRAWING NUMBER: | REVISION: | PAGE: |
|----------------------------|-----------|-----------------|-----------|-------|
|                            |           |                 |           | FAGL. |
| PRINT VERSION NOT TO SCALE | NON JEDEC | 98ASA01485D     | А         | 6     |

Figure 8. Package outline (DFN 7 mm × 6.5 mm) — notes

#### Airfast RF Power GaN Amplifier

## **14 Product documentation and software**

Refer to the following resources to aid your design process.

### Application notes

- AN1907: Solder Reflow Attach Method for High Power RF Devices in Plastic Packages
- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

#### Software

• .s2p File

## **15 Revision history**

The following table summarizes revisions to this document.

 Table 14. Revision history

| Revision | Date              | Description   |
|----------|-------------------|---|
| 0        | 13 September 2022 | Initial release of data sheet   |
| 1        | 30 November 2022  | <ul> <li>Table 1, Maximum Ratings: Gate-Source Voltage: updated –8, 0 to –16, 0 Vdc, p. 2</li> <li>General updates made to align data sheet to current standard</li> </ul>  |
| 2        | 18 October 2023   | <ul> <li>Figure 2, Product Marking: added, p. 2</li> <li>Table 3, Product Marking Trace Code: added, p. 2</li> <li>Table 11, Functional Tests: updated output power test condition, p. 5</li> <li>General updates made to align data sheet to current standard</li> </ul> |

# 16 Legal information

## 16.1 Data sheet status

| Document status <sup>[1][2]</sup> | Product status <sup>[3]</sup> | Definition  |
|-----------------------------------|-------------------------------|---|
| Objective [short] data sheet      | Development                   | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet    | Qualification                 | This document contains data from the preliminary specification.                       |
| Product [short] data sheet        | Production                    | This document contains the product specification.                                     |

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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